



Features

- Proprietary α SiC MOSFET technology
- Low loss, with low $R_{DS, ON}$
- Fast switching with low R_G and low capacitance
- Optimized gate drive voltage ($V_{GS} = 15\text{V}$)
- Low reverse recovery diode (Q_{rr})
- AEC-Q101 Automotive Qualified

Product Summary

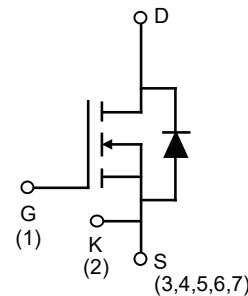
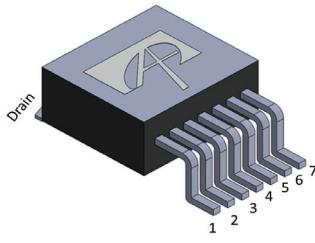
$V_{DS} @ T_{J, max}$	1200 V
I_{DM}	40 A
$R_{DS(ON)}$, typ	150 m Ω
Q_{rr}	73 nC
$E_{oss} @ 800\text{V}$	18 μJ
100% UIS Tested	

Applications

- xEV Charger
- Electric Vehicle Supply Equipment (EVSE)
- Motor Drives
- Automotive Inverters



Pin Configuration



Ordering Part Number	Package Type	Form	Shipping Quantity
AOBB150V120X2Q	TO-263-7L	Tape & Reel	800/Reel

Absolute Maximum Ratings

($T_A = 25^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter		AOBB150V120X2Q	Units
V_{DS}	Drain-Source Voltage		1200	V
$V_{GS, MAX}$	Gate-Source Voltage	Maximum	-8/+18	V
$V_{GS,OP,TRANS}$		Max Transient ^(A)	-8/+20	
$V_{GS,OP}$		Recommended Operating ^(B)	-5/+15	
I_D	Continuous Drain Current	$T_C = 25^\circ\text{C}$	19	A
		$T_C = 100^\circ\text{C}$	13	
I_{DM}	Pulsed Drain Current ^(C)		40	
I_{SD}	Continuous Body Diode Forward Current ($V_{GS} = -5\text{V}$)		21	
E_{AS}	Single Pulsed Avalanche Energy ^(D)		90	mJ
P_D	Power Dissipation ^(C)	$T_C = 25^\circ\text{C}$	107	W
T_J, T_{STG}	Junction and Storage Temperature Range		-55 to 175	°C
T_L	Maximum lead temperature for soldering purpose, 1/8" from case for 5 seconds		245	°C

Thermal Characteristics

Symbol	Parameter	Typ	Max	Units
R _{θJA}	Maximum Junction-to-Ambient ^(E,F)		40	°C/W
R _{θJC}	Maximum Junction-to-Case ^(G)	1.2	1.4	°C/W

Electrical Characteristics

(T_J = 25°C, unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV _{DSS}	Drain-Source Breakdown Voltage	I _D =250 μA, V _{GS} =0 V, T _J =25°C I _D =250 μA, V _{GS} =0 V, T _J =150°C	1200			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =1200 V, V _{GS} =0 V			100	μA
I _{GSS}	Gate-Body Leakage Current	V _{DS} =0 V, V _{GS} =+15/-5 V			±100	nA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =3.9 mA	1.7	2.8	3.8	V
R _{DS(ON)}	Static Drain-Source On-resistance	V _{GS} =15 V, I _D =3.9 A	T _J =25°C T _J =150°C	150	195	mΩ
g _{FS}	Forward Transconductance	V _{DS} =20 V, I _D =3.9 A		5.7		S
V _{SD}	Diode Forward Voltage	I _S =3.9 A, V _{GS} =-5 V		4	5	V
DYNAMIC PARAMETERS						
C _{iss}	Input Capacitance	V _{GS} =0 V, V _{DS} =800 V, f=1 MHz		664		pF
C _{oss}	Output Capacitance			42.2		pF
C _{rss}	Reverse Transfer Capacitance			5.2		pF
E _{oss}	C _{oss} Stored Energy			18		μJ
R _G	Gate Resistance	f=1 MHz	1.2	2.1	3.2	Ω
SWITCHING PARAMETERS						
Q _g	Total Gate Charge	V _{GS} =-5/+15 V, V _{DS} =800 V, I _D =3.9 A		27.9		nC
Q _{gs}	Gate Source Charge			8.9		nC
Q _{gd}	Gate Drain Charge			14.3		nC
t _{D(on)}	Turn-on Delay Time	V _{GS} =-5 V/+15 V, V _{DS} =800 V, I _D =9 A, R _{G,ON} =2 Ω, R _{G,OFF} =0 Ω L=120 μH FWD: AOBB150V120X2Q		5.5		ns
t _r	Turn-on Rise Time			5.7		ns
t _{D(off)}	Turn-off Delay Time			8.5		ns
t _f	Turn-off Fall Time			18.3		ns
E _{on}	Turn-on Energy			88		μJ
E _{off}	Turn-off Energy			16		μJ
E _{tot}	Total Switching Energy			104		μJ
t _{rr}	Body Diode Reverse Recovery Time			25		ns
I _{rm}	Peak Reverse Recovery Current	I _F =9 A, dI/dt=1000 A/μs, V _{DS} =800 V		5.5		A
Q _{rr}	Body Diode Reverse Recovery Charge			73		nC

Notes:

- A. t_{pulse} < 1 μs, f > 1 Hz
- B. Device can be operated at V_{GS}=0/15 V. Actual operating V_{GS} will depend on application specifics such as parasitic inductance and dV/dt but should not exceed maximum ratings.
- C. The power dissipation P_D is based on T_{J(MAX)}=175°C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.
- D. L=5 mH, I_S=6 A, R_G=25 Ω, Starting T_J=25°C.
- E. The value of R_{θJA} is measured with the device in a still air environment with T_A=25°C.

- F. The R_{θJA} is the sum of the thermal impedance from junction to case R_{θJC} and case to ambient.
- G. The value of R_{θJC} is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of T_{J(MAX)}=175°C.
- H. The static characteristics in Figures 1 to 8 are obtained using <300 μs pulses, duty cycle 0.5% max.
- I. These curves are based on R_{θJC} which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of T_{J(MAX)}=175°C. The SOA curve provides a single pulse rating.

Typical Electrical and Thermal Characteristics

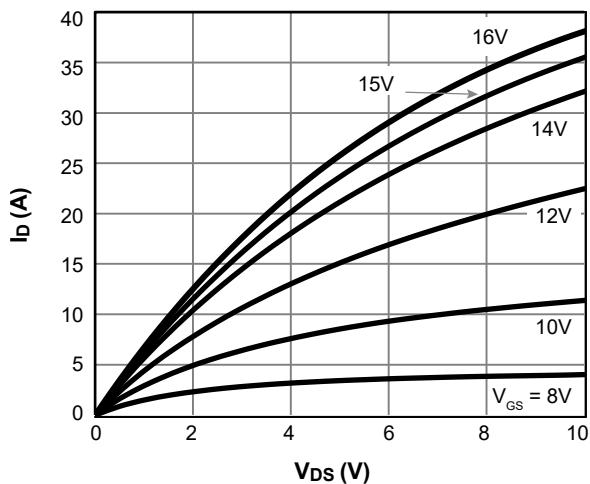


Figure 1. On-Region Characteristics $T_J = 25^\circ\text{C}$

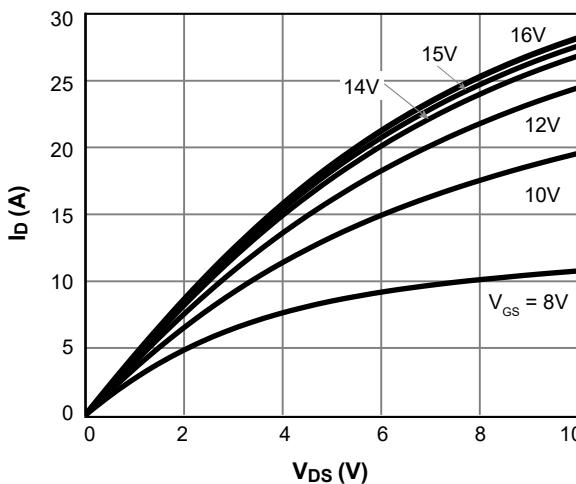


Figure 2. On-Region Characteristics $T_J = 175^\circ\text{C}$

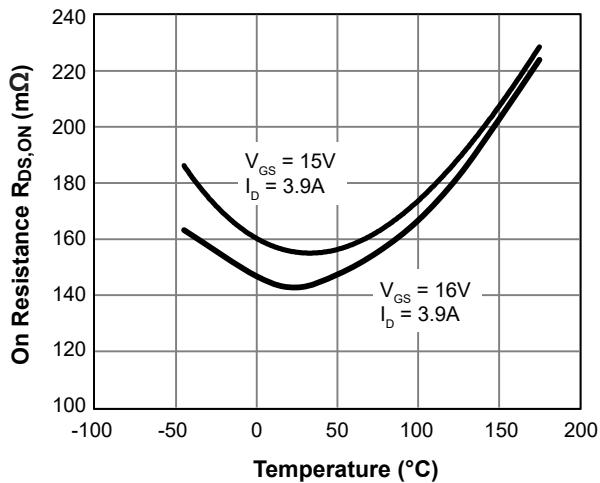


Figure 3. On Resistance vs. Junction Temperature

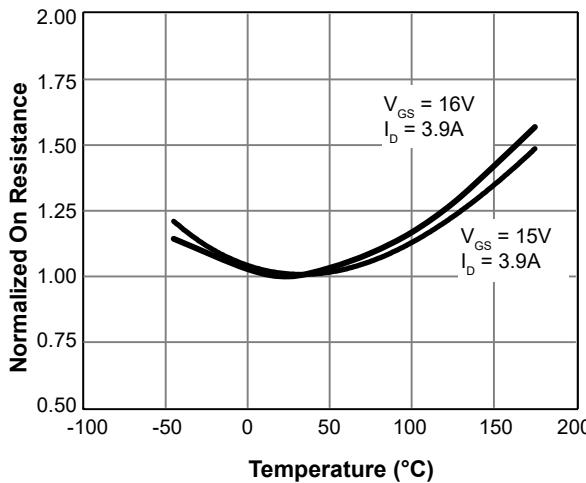


Figure 4. Normalized On Resistance vs. Junction Temperature

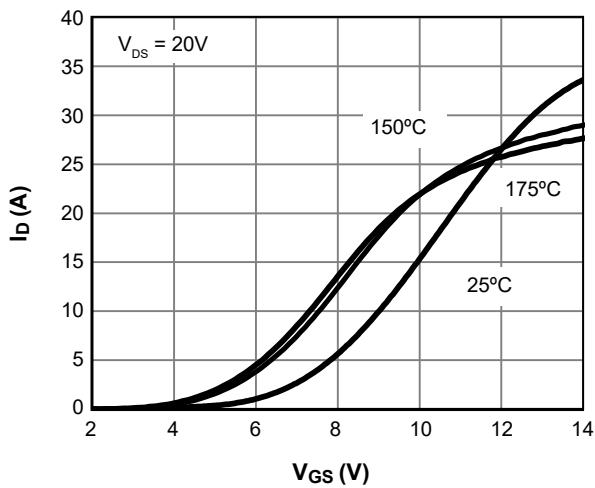


Figure 5. Transfer Characteristics

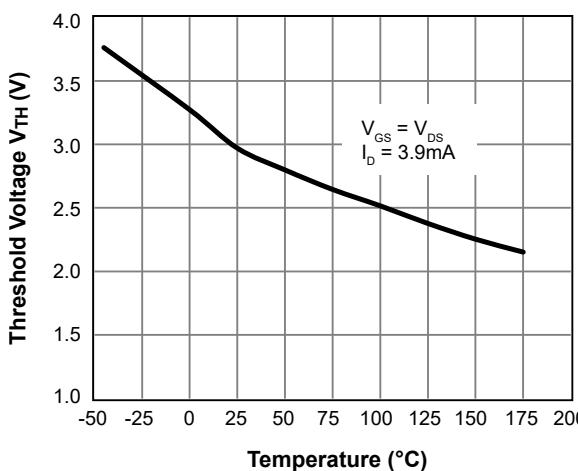


Figure 6. Threshold Voltage vs. Junction Temperature

Typical Electrical and Thermal Characteristics (Continued)

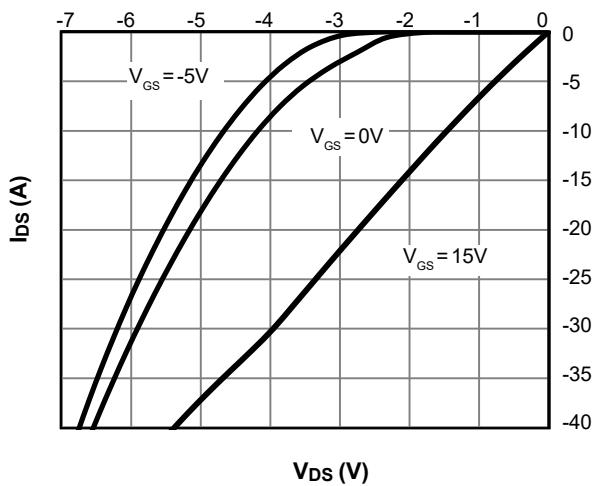


Figure 7. Body-diode Characteristics at 25°C

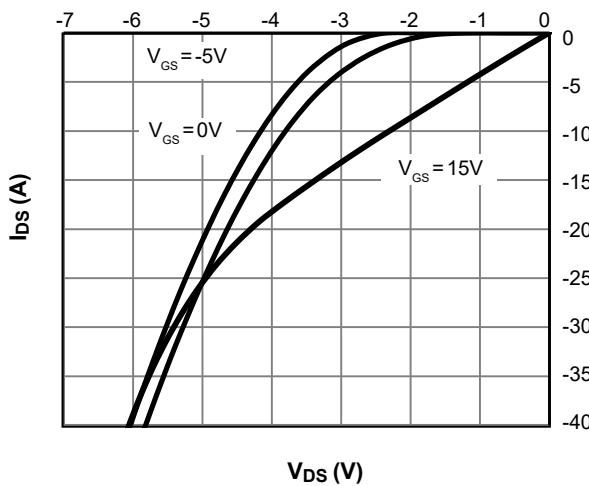


Figure 8. Body-diode Characteristics at 175°C

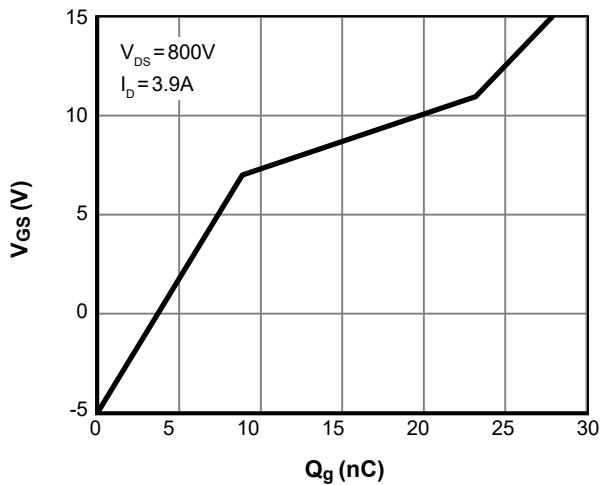


Figure 9. Gate-charge Characteristics

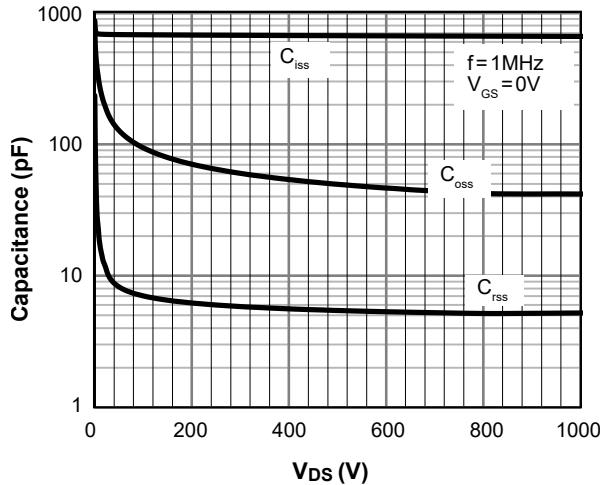


Figure 10. Capacitance Characteristics

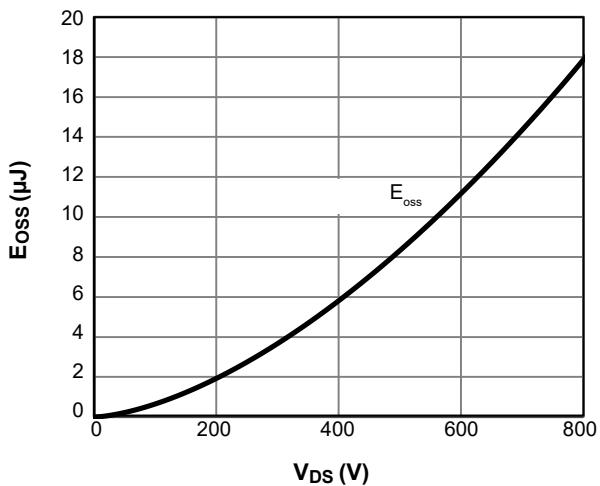


Figure 11. E_{oss} Stored Energy

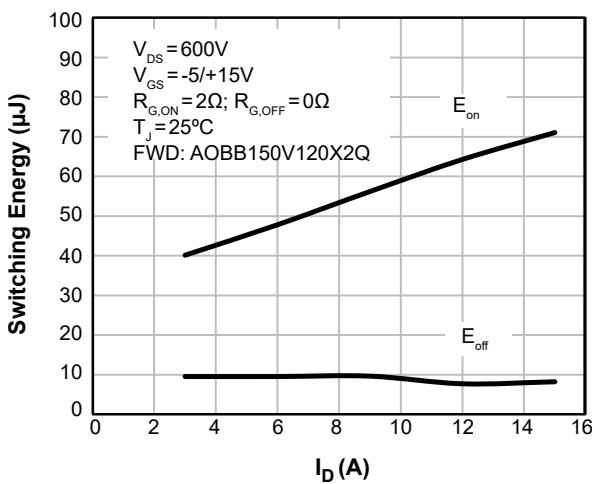


Figure 12. Switching Energy vs. Drain Current

Typical Electrical and Thermal Characteristics (Continued)

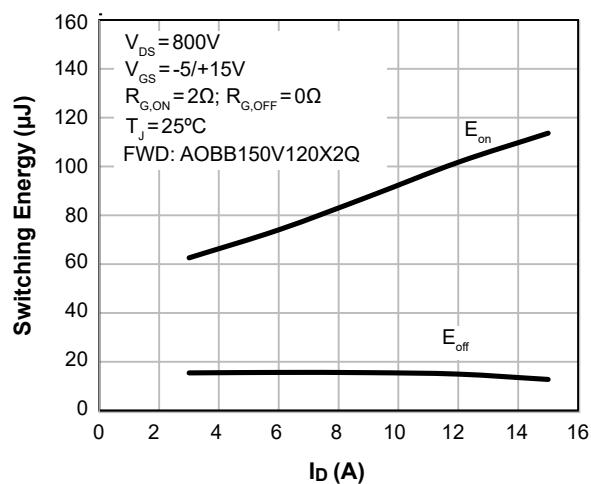


Figure 13. Switching Energy vs. Drain Current

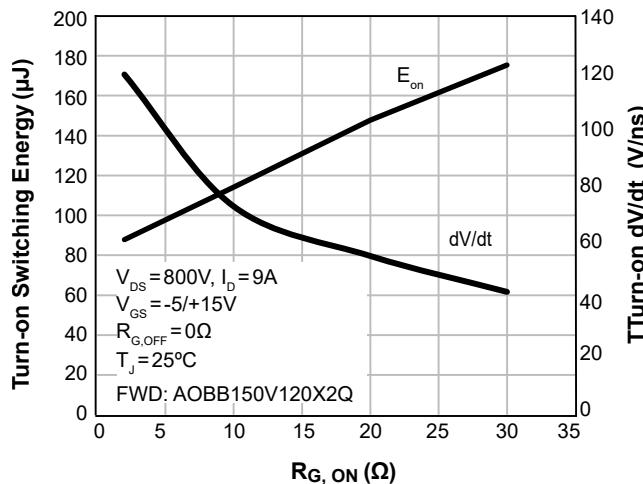


Figure 14. Turn-on Energy and dV/dt vs. External Gate Resistance

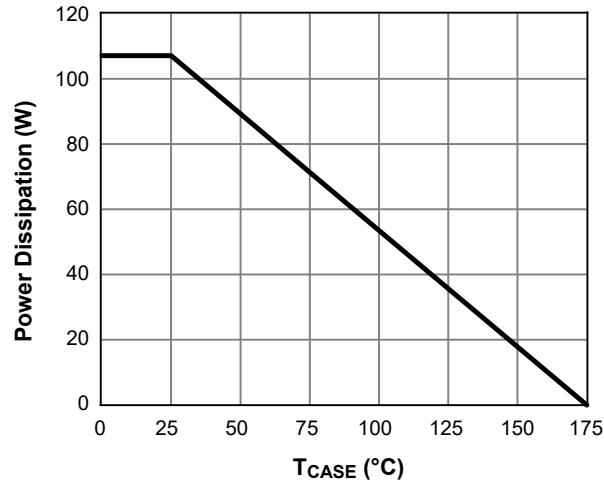


Figure 15. Power De-rating (Note I)

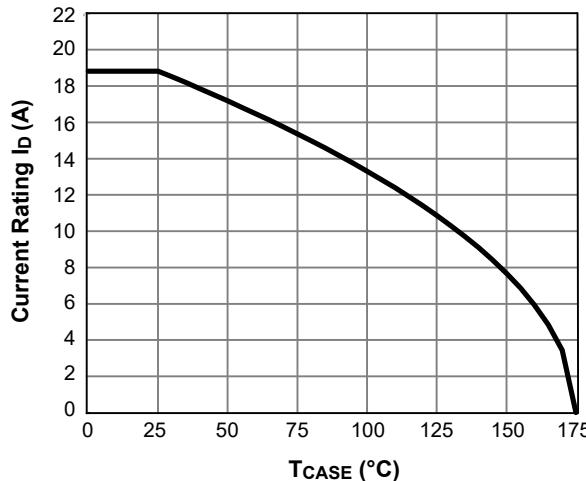


Figure 16. Current De-rating (Note I)

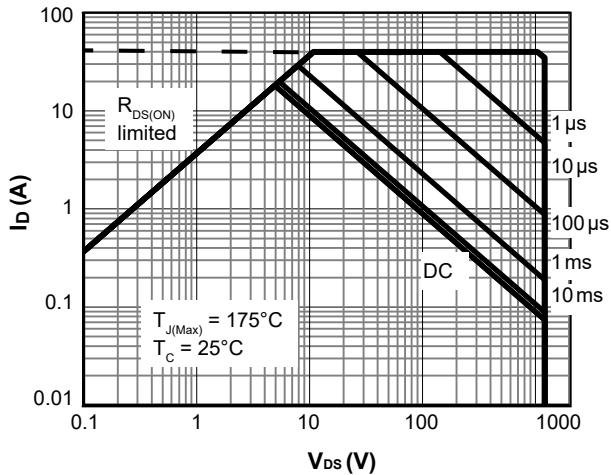


Figure 17. Maximum Forward Biased Safe Operating Area for AOBB150V120X2Q (Note I)

Typical Characteristics and Thermal Characteristics (Continued)

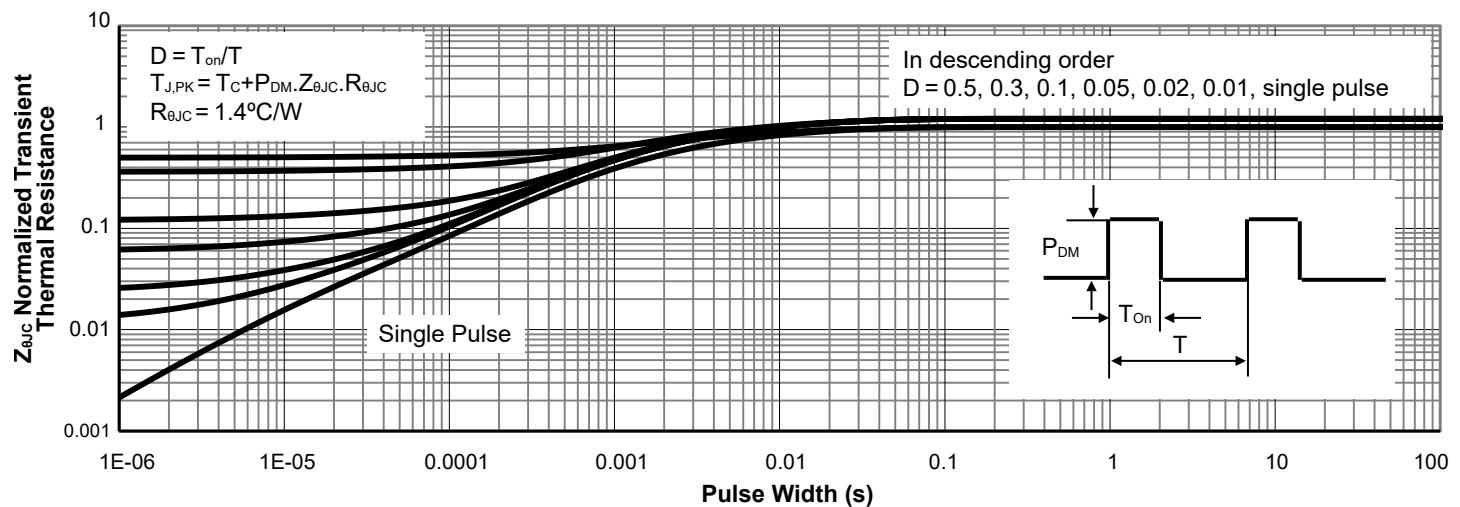


Figure 18. Normalized Maximum Transient Thermal Impedance for AOBB150V120X2Q (Note I)

Test Circuits and Waveforms

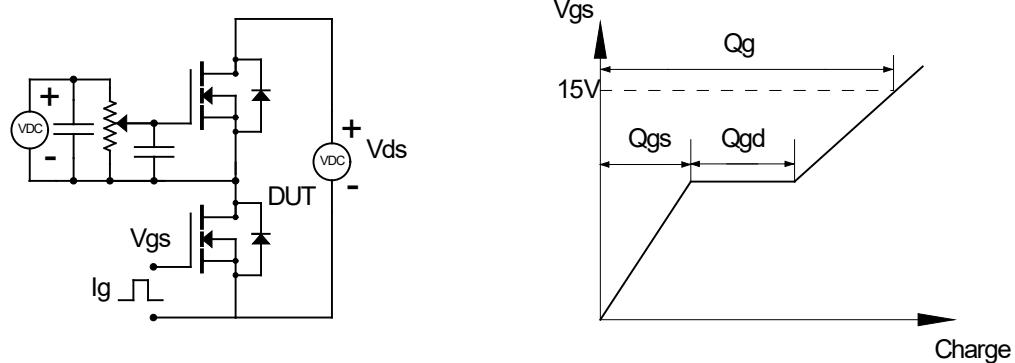


Figure 19. Gate Charge Test Circuits and Waveforms

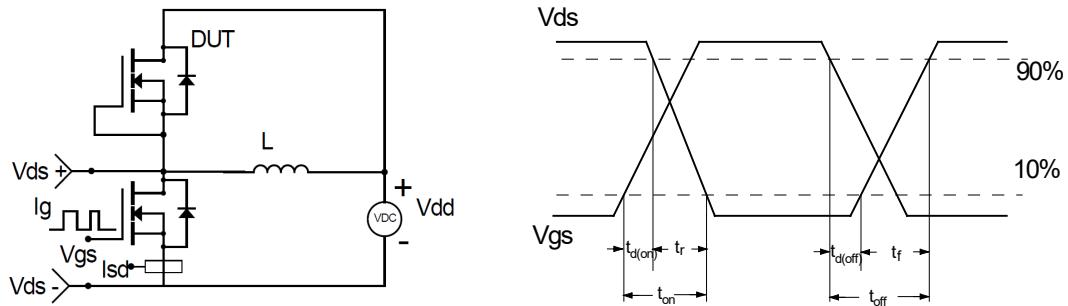


Figure 20. Inductive Switching Test Circuit and Waveforms

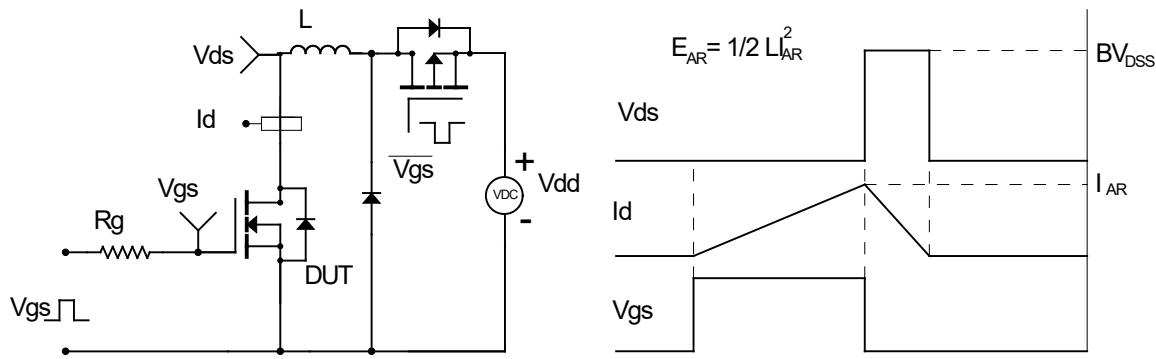


Figure 21. Unclamped Inductive Switching (UIS) Test Circuit and Waveforms

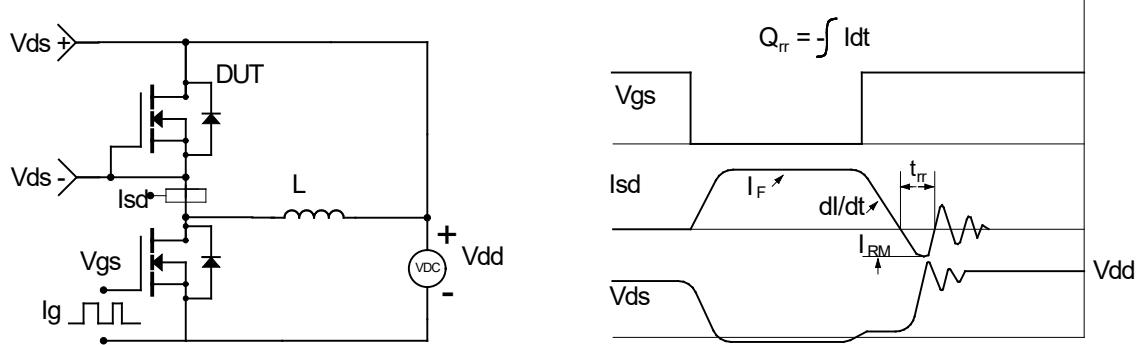
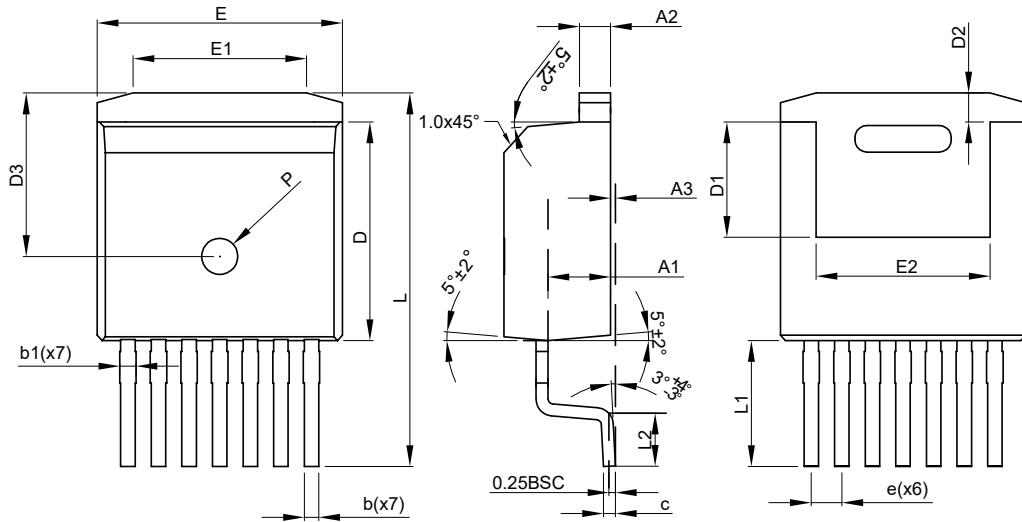


Figure 22. Diode Recovery Test Circuits and Waveforms

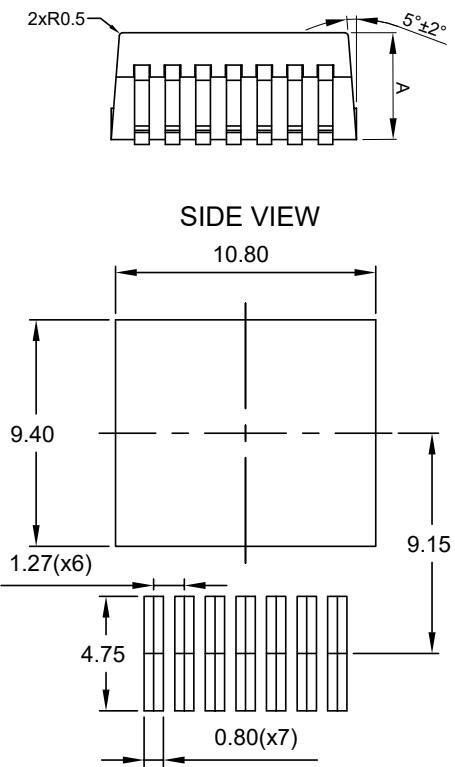
Package Dimensions, TO-263-7L



TOP VIEW

SIDE VIEW

BOTTOM VIEW



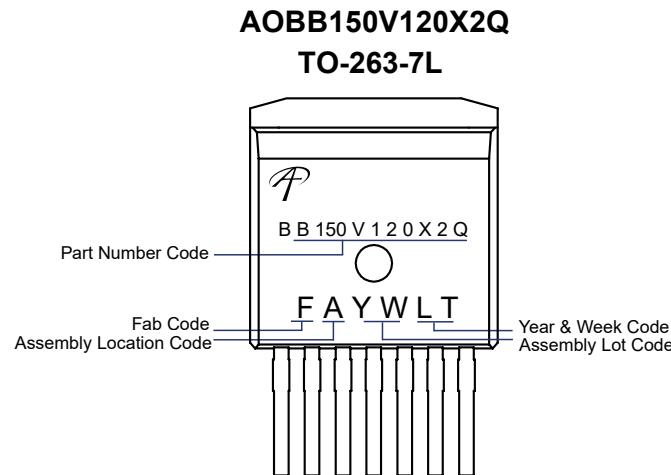
RECOMMENDED LAND PATTERN

SYMBOLS	DIM. IN MM			DIM. IN INCH		
	MIN.	NOM.	MAX.	MIN.	NOM.	MAX.
A	4.30	4.43	4.56	0.169	0.174	0.180
A1	2.45	2.60	2.75	0.096	0.102	0.108
A2	1.20	1.30	1.40	0.047	0.051	0.055
A3	0.00	0.13	0.25	0.000	0.005	0.010
b	0.50	0.60	0.70	0.020	0.024	0.028
b1	0.60	0.70	0.90	0.024	0.028	0.035
c	0.45	0.50	0.60	0.018	0.020	0.024
D	8.93	9.08	9.23	0.352	0.357	0.363
D1	4.65	4.80	4.95	0.183	0.189	0.195
D2	0.98	1.20	1.42	0.039	0.047	0.056
D3	6.48	6.78	7.08	0.255	0.267	0.279
E	10.08	10.18	10.28	0.397	0.401	0.405
E1	6.50	7.00	7.50	0.256	0.276	0.295
E2	6.92	7.22	7.52	0.272	0.284	0.296
e	1.27BSC			0.05BSC		
L	15.00	15.50	16.00	0.591	0.610	0.630
L1	5.09	5.22	5.33	0.200	0.206	0.210
L2	1.90	2.20	2.50	0.075	0.087	0.098
P	1.40	1.50	1.60	0.055	0.059	0.063

NOTE:

1. CONTROLLING DIMENSION IS MILLIMETER.
CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.
2. DOTTED OUTLINE IS GUIDELINE TO BE COMPATIBLE WITH
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Part Marking



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